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Session A: Modeling and Simulation

Measurement-Based Modeling of Backhaul Communication Systems of Complex Terrain

(Invited Talk)...N/A Julius Kusuma Facebook Connectivity Lab

On the Formalism of Heterodyne Mixer Phase Synchronization in Microwave Receivers...1

Loren Betts Keysight Technologies

Basics Investigation of Electromagnetic Sensing for Wood Moisture contents...10

Masahiro Horibe¹, Yuka Miyoshi² ¹National Institute of Advanced Industrial Science (AIST), ²Forest Research and Management Organization

Simple Trapping Model for GaN HEMTs...14

John Wood¹, Zul Mokhti², Yueying Liu¹ ¹Wolfspeed, Research Triangle Park, ²Wolfspeed, Morgan Hill

Investigation on practical problems in on-wafer measurement for actual Devices...17 Ryo Sakamaki, Masahiro Horibe

National Institute of Advanced Industrial Science (AIST)

A Comparison of Terahertz Permittivity Measurements of Several Dielectric Materials Using Frequency and Time Domain Methods...20

Christopher Green and Jeffrey Seligman The University of Arizona

Session B: Metrology

Multiphysics Phase-Field Method to Study Electroformation of Memristive Dielectric Thin Films (Invited Talk)...N/A

John Sevic Embry–Riddle Aeronautical University

Updates to the traceability of mm-wave power measurements at NIST ... 24

Aaron Morgan Hagerstrom, Angela Stelson, Jeff Jargon, and Christian Long National Institute of Standards and Technology

Robust mTRL implementation for probing standards manufactured on PCBs...28

Michael E Gadringer Graz University of Technology

On the Influence of Thru- and Line-Length-Related Effects in CPW-Based Multiline TRL Calibrations...32

Gia Ngoc Phung and Uwe Arz Physikalisch-Technische Bundesanstalt (PTB)

Pre-Silicon direct Calibration/De-embedding Evaluation and Device Parameters Uncertainty Estimation...36

C. Esposito¹, C. De Martino^{2,3}, S. Lehmann⁴, Zhixing Zhao⁴, M. Schroter¹, M. Spirito² ¹Technical University Dresden, ²Delft University of Technology, ³Vertigo Technologies, ⁴ Global Foundries

Precision Offset Short Calibration Standards for 1.35 mm Coaxial Line Sizes...40

Masahiro Horibe, Ryo Sakamaki National Institute of Advanced Industrial Science (AIST)

P Broadband Characterization of Co-planar GSG Wirebonds for RF Heterogeneous 2.5D Integration...44

Ziad Hatab, Erich Leitgeb, Michael E. Gadringer Graz University of Technology

Session C: Measurements

Linearity Characterization of the Self-Enhanced Class J PA Operating Mode through Modulated-Signal Load-Pull Measurements...48

Frederik Vanaverbeke¹, Michael B. Satinu¹, Michele Squillante², Kevin Kim¹ NXP Semiconductors, ²Anteverta-mw B.V.

Automated Noise-Parameter Measurements of Cryogenic LNAs...56

Alexander Sheldon¹, Leonid Belostotski¹, Hamdi Mani², Christopher E. Groppi², Karl F. Warnick³ ¹University of Calgary, Canada, ²Arizona State University, ³Brigham Young University

Combined Wideband Active Load-Pull and Modulation Distortion Characterization with a Vector Network Analyzer...60

Alberto Maria Angelotti¹, Gian Gibiino¹, Alberto Santarelli¹, Troels Nielsen², Jan Verspecht² ¹University of Bologna, ²Keysight Technologies

Issues of Multi-Notch NPR Characterization Procedures...64

Ricardo Figueiredo, Nuno Borges Carvalho Universidade de Aveiro

Characterization of the frequency dependent match for optimal performance of wideband power amplifiers...68

Sanket Chaudhary¹, Marina Jordao¹, Nuno Borges Carvalho¹, Marc Vanden Bossche², Adam Cooman³ ¹Universidade de Aveiro, ² National Instruments Corporation, ³Ampleon

Session D: OTA

On Over-the-Air Far-Field Measurements Below Fraunhofer Distance...72

Jan Fromme, Jiaju Cai, Vincent Kotzsch, Gerardo Orozco, Marc Vanden Bossche National Instruments Corporation

The Antenna Dome Real-Time Distributed Antenna Pattern Characterization System...76

F.A. Musters¹, R.A. Coesoij¹, M.D. Migliore², F. Schettino², M. Spirito¹ ¹Delft University of Technology, ²Universita' degli studi di Cassino e del Lazio Meridionale,

Novel EM-Field Measurement Method by Using a Lambda/2 Dipole LED Antenna as a Signal Strength Indicator...81

Daiki Ikeno¹, Yuji Koita¹, Masashi Nakatsugawa¹, Tamami Maruyama¹, Yasuhiro Tamayama² ¹National Institute of Technology, Hakodate College, ²Nagaoka University of Technology

Extended Range mmWave for Fixed Wireless Application...N/A

Randall S Fassbinder¹, Laetitia Falconetti³, Sam Guirguis², Elisiario Cunha Neto³, Arturo Ortega², Narothum Saxena¹, Michael Chard², Kausik Ray Chaudhuri², Atanu Halder¹, Rahul D Patel³, and Michael Irizarry¹ ¹US Cellular Corporation, ²Qualcomm Engineering Services, ³Ericsson

Design and Realization of a Compact Size Active Antenna for UHF Satellite Communication...85

Abdellatif Bouyedda¹, Bruno Barelaud¹, Laurent Gineste² ¹XLIM, ²Exotic Systems

Calibration Method for an RF I-V Based HF RFID Impedance Measurement System...89

Benjamin J. B. Deutschmann¹, Michael E Gadringer¹, Richard Fischbacher¹, Lukas Görtschacher², Franz Amtmann², Erich Merlin², Ulrich Muehlmann², and Jasmin Grosinger¹ ¹Graz University of Technology, ²NXP Semiconductors Austria GmbH

Dynamic Range Definitions and Measurement Applied To Radar Digital Receiver Exciter (DREX)...N/A

John O Mortensen¹, Rick Sturdivant², and Mark Wickert¹ ¹University of Colorado, ²MPT Inc.